

Notice of References Cited

Application/Control No.	Applicant(s)/Pate	nt Under	
09/854,919	Reexamination BAUMANN ET AL.		
Examiner	Art Unit		
Tho y Duona	3743	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6450276	09-2002	Alexandru Latcau	180/68.4
	В	US-5875836	03-1999	Katsumi Nakamura	165/122
	O	US-5671803	09-1997	Tepas et al.	165/41
	D	US-5658041	08-1997	Girardot et al.	180/68.4
	E	US-4951737	08-1990	Tenhundfeld et al.	165/76
	F	US-2715448	08-1955	E. G. Zeeb	180/68.4
	G	US-5271473	12-1993	Ikeda et al.	180/68.4
	Н	US-4141426	02-1979	Hamada et al.	180/68.4
	1	US-4821828	04-1989	Schwerzler et al.	180/68.4
	J	US-			
	Κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z	EP 0178266	04-1986	Europe	Marcello et al.	
	0					
	Р					
	α					
	R					
	s					
	Т					•

NON-PATENT DOCUMENTS

	TOTAL DOCUMENTO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	٧				
	w				
	x				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.